## Notice of References Cited Application/Control No. 10/644,195 Examiner David S. Blum Applicant(s)/Patent Under Reexamination HYODO ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0100175 A1	05-2003	Nobutoki et al.	438/623
*	В	US-2004/0137757 A1	07-2004	Li et al.	438/778
	C	US-			
	D	US-			
	E	US-	·		
	F	US-			
	G	US-			
	Н	US-			
	. 1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	σ					
	Ŕ					·
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v .	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.